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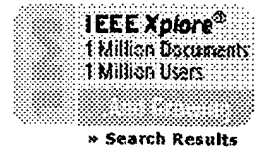
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Nguyen-Vo, N.-M.; Pfeifer, S.J.;

Quantum Electronics, IEEE Journal of, Volume: 29, Issue: 2, Feb. 1993

Pages:508 - 514

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